

APPROVAL SHEET

MULTILAYER CERAMIC CAPACITORS

Low Profile Series

0402 to 1210 Sizes

X7R, X5R & Y5V Dielectrics

Halogen Free & RoHS Compliance



*Contents in this sheet are subject to change without prior notice.



1. DESCRIPTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC TT series MLCC is used in product having thickness concerned generally have high capacitance and thinner product thickness. The high dielectric constant material X7R, X5R and Y5V are used for this series product.

2. FEATURES

- a. Standard size with thin thickness.
- b. Small size with high capacitance.
- c. Capacitor with lead-free termination (pure Tin).

3. APPLICATIONS

- a. For LCD panels.
- b. For PCMCA cards.
- c. For IC packaging and modules.
- d. Any thickness concerned products.

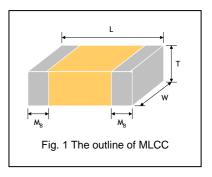
4. HOW TO ORDER

<u>TT</u>	<u>15</u>	<u>X</u>	<u>475</u>	<u>M</u>	<u>6R3</u>	<u>C</u>	Ī
<u>Series</u>	Size	Dielectric	<u>Capacitance</u>	Tolerance	Rated voltage	<u>Termination</u>	<u>Packaging</u>
	45 0400 (4005)	D V7D	Z NE LE K	1/4 × 1		• • • • • • • • • • • • • • • • • • • •	
TT=Low profile	15 =0402 (1005)	B=X/R	Two significant	K =±10%	Two significant	C =Cu/Ni/Sn	T=7" reeled
	18 =0603 (1608)	X =X5R/+//	digits followed by	M=±20%	digits followed by		G=13" reeled
	21 =0805 (2012)	F=Y5V	no. of zeros. And	Z =-20/+80%	no. of zeros. And		
	31 =1206 (3216)		R is in place of		R is in place of		
	32 =1210 (3225)		decimal point.	5A	decimal point.		
		8	eg.:	TEM ALLIANCE	6R3 =6.3 VDC		
		9					
		器	475=47x10 ⁵		100 =10 VDC		
		195	=4,700,000pF		160 =16 VDC		
		C	=4.7µF	10.	250 =25 VDC		
			A/co Chno	CO/Z	500 =50 VDC		
			JEQUE .	UBY TON	101 =100 VDC		



5. EXTERNAL DIMENSIONS

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Sy	mbol	M _B (mm)
0402 (1005)	1.00±0.2	0.5±0.2	0.30±0.03	L	0.25±0.10
0603 (1608)	1.6+0.15/-0.10	0.8+0.15/-0.10	0.50±0.10	Н	0.40±0.15
0805 (2012)	2.00±0.20	1.25±0.20	0.85±0.10	Т	0.50±0.20
1206 (2216)	2 20 . 0 20	1.60±0.20	0.85±0.10	Т	0.60.0.20
1206 (3216)	3.20±0.20	1.60±0.20	1.15±0.15	J	0.60±0.20
1210 (2225)	3.20±0.30	2.50±0.20	0.85±0.10	Т	0.75±0.25
1210 (3225)	3.20±0.30	2.50±0.20	2.00±0.20	K	0.75±0.25



6. GENERAL ELECTRICAL DATA

Dielectric	X7R	X5R	Y5V				
Size		0402, 0603, 0805, 1206, 1210					
Capacitance range*	1μF to 10μF	1μF to 10μF					
Capacitance tolerance**	K (±10%	K (±10%), M (±20%) Z (-20/					
Rated voltage (WVDC)	10V, 16V, 25V, 50V, 100V	6.3V, 10V, 16V, 25V	10V, 16V, 25V, 50V				
Operating temperature	-55 to +125℃	-55 to +85℃	-25 to +85℃				
Capacitance characteristic	±15% +30/-80%						
Termination	47/17	Ni/Sn (lead-free termination)					

^{*} Measured at 1.0±0.2Vrms, 1.0kHz±10%, 30~70% related humidity, 25°C ambient temperature for X7R, X5R and at 20°C for Y5V.

^{**} Preconditioning for Class II MLCC: Perform a heat treatment at 150±10°C for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.



^{*} Reflow soldering process only is recommended.

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7. CAPACITANCE RANGE

7-1 X7R dielectric

	Dielectric						X7R					
	Size		0805			1206			1210			
Rate	ed voltage (VDC)	10	16	25	50	10	16	25	50	10	16	100
	1.0µF (105)							Т				
a)	1.5µF (155)											
Capacitance	2.2µF (225)		Т	Т					Т			K
ita	3.3µF (335)											
ac	4.7μF (475)	Т						Т				
Sag	6.8µF (685)											
	10μF (106)					Т						
	22μF (226)											

7-2 X5R dielectric

	Dielectric)	K5R								
	Size		0402		0603 0805		05	1206				1210						
Rate	ed voltage (VDC)	6.3	10	25	10	16	6.3	10	16	25	6.3	10	16	25	50	10	16	25
	0.22uF (224)			L	Н	Н												
	0.47uF (474)	L		L														
	1.0µF (105)	L			Н	Н		Т	Т	Т		Т	Т	Т				
e	1.5µF (155)							Т	T			Т	Т	Т				
au	2.2µF (225)	L					J	LT.	T	J		Т	Т	Т	Т			
cit	3.3µF (335)					14	775	=	_/~	7		Т	Т	Т		Т		
Capacitance	4.7µF (475)	L			H	NA.	T	пT	ηT	T		Т	Т	Т		Т		
ပိ	6.8µF (685)				/IX		场	权1	刀凑	- , ~ ;	2							
	10µF (106)				140	*	$\lambda \tau$	T	T	1500	×0,0	J/T		Т		Т		Т
	22uF (226)				144177	XXX)	Т	Т		<f -<="" th=""><th>T</th><th>15</th><th>Т</th><th></th><th></th><th></th><th>Т</th><th></th></f>	T	15	Т				Т	
	47uF (476)				774						T							

7-3 Y5V dielectric

	Dielectric						Y5V				
	Size		0805 1206					1210			
Rate	ed voltage (VDC)	10	16	25	50	10	16	25	50	10	16
	1.0µF (105)		1	0,	T		(O ₂ ,	\$2/			
a)	1.5µF (155)			4/11	Crh.		0110	3.			
ğ	2.2µF (225)		T	125/1		OIOEA,	,T///	T	Т		
草	3.3µF (335)	Т			COHMOIA	OL CORROD	ITION.				
Capacitance	4.7μF (475)	Т	T		MANTA	JY LUKYUN	T				
ğ	6.8µF (685)					T					
	10μF (106)	Т				Т				Т	
	22μF (226)										

8. PACKAGING STYLE AND QUANTITY

Size	Thickness May (mm	VC. maked	7" reel			
Size	Thickness Max (mm	//Symbol	Paper tape	Plastic tape		
0402 (1005)	0.33	L	15k	-		
0603 (1608)	0.60	Н	4k	-		
0805 (2012)	0.95	Т	4k	-		
4000 (0040)	0.95	Т	4k	-		
1206 (3216)	1.30	J	-	3k		
1210 (2225)	0.95	Т	-	3k		
1210 (3225)	2.00	K	-	1k		

Unit: pieces



9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Test Condition	Requirements				
1.	Visual and		* No remarkable defect.				
	Mechanical		* Dimensions to conform to individual specification sheet.				
_		Cap≤10μF, 1.0±0.2Vrms, 1kHz±10%	* Shall not exceed the limits given in the detailed spec				
	Capacitance	Cap>10µF, 0.5±0.2Vrms, 120Hz±20%**	* Shall not exceed the limits given in the detailed spec.				
3.	Q/ D.F.	** Test condition: 0.5±0.2Vrms,1KHz±10%	X7R/X5R: Rated vol. D.F.				
	(Dissipation	TT18X≧475(10V) , TT15X series	100V ≤5%				
	Factor)	*Defere initial massurement (Class II only). To apply do aging	50V, 25V, 16V, 10V ≤10% 6.3V ≤15%				
		*Before initial measurement (Class II only): To apply de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.	Y5V:				
		a. 100 0 101 111 alon 001101 2 1 <u>22</u> 1110 at 100111 tomp 1	Rated vol. D.F.				
			50V ≤7%				
			25V ≤9%				
		* To apply valtage: 2500/ rated valtage	16V/10V ≤12.5%				
4.	Dielectric	* To apply voltage: 250% rated voltage. * Duration: 1 to 5 sec.	* No evidence of damage or flash over during test.				
	Strength	* Charge and discharge current less than 50mA.					
5.	Insulation	* To apply rated voltage for max. 120 sec.	≥10GΩ or RxC≥100Ω-F whichever is smaller.				
٠.	Resistance		- 100 - 100 - 100 - 1 miles 100 - 10				
6.		With no electrical load.					
0.	remperature	T.C. Operating Temp	T.C. Conscitones Change				
	Coefficient	X7R -55~125℃ at 25℃	T.C. Capacitance Change				
		X5R -55~85°C at 25°C Y5V -25~85°C at 20°C	X7R Within ±15% X5R Within ±15%				
		*Before initial measurement (Class II only):	Y5V Within +30%/-80%				
		To apply de-aging at 150℃ for 1hr then set for 24± 2 hrs at	VVIIIII 10070/ 0070				
		room temp.					
		01005 0201 Cap≤0.01µF: 0.5V Cap<0.1µF:1V					
		Cap>0.01µF: 0.2V 0.1µF*≤Cap<1µF: 0.2V					
		Cáp≥1μF: 0.1V *0201X104/16V: 0.5V					
		0402 0603					
		Cap<1µF: 1V					
		1μF <cap<10μf: 0.2v="" cap="">4.7μF: 0.2V</cap<10μf:>	TANGS				
		Cap≥10µF: 0.1V PASSIVE SYSTEM AL 0805 1206/1210	SE				
		Cap<10μF: 1V	2000				
		Cap>10µF: 0.5V Cap>100µF: 0.5V Cap>100µF: 0.2V					
7.	Adhesive	* Pressurizing force : 5N (≤0603) and 10N (>0603) * Test time: 10±1 sec.	* No remarkable damage or removal of the terminations.				
	Strength of	lest time. To 17 sec.					
	Termination	ECHNOLOGY CORROLL					
8.	Vibration	* Vibration frequency: 10~55 Hz/min.	* No remarkable damage.				
	Resistance	* Total amplitude: 1.5mm	* Cap change and Q/D.F.: To meet initial spec.				
		* Test time: 6 hrs. (Two hrs each in three mutually perpendicular directions.)					
		* Before initial measurement (Class II only):					
		To apply de-aging at 150℃ for 1hr then set for 24± 2 hrs at					
		room temp.					
		* Cap./DF(Q) Measurement to be made after de-aging at					
C	Caldana I: III.	150℃ for 1hr then set for 24±2 hrs at room temp. * Solder temperature: 235±5℃	OFD/ min appears of all matalias				
9.	Solderability	* Dipping time: 2±0.5 sec.	95% min. coverage of all metalized area.				
10.	Bending Test	* The middle part of substrate shall be pressurized by means	* No remarkable damage.				
]	of the pressurizing rod at a rate of about 1 mm per second unti					
		the deflection becomes 1 mm and then the pressure shall be	X7R/X5R: within ±12.5%				
		maintained for 5±1 sec. * Before initial measurement (Class II only):					
		To apply de-aging at 150°C for 1hr then set for 24±2 hrs at	Y5V: within ±30% (This capacitance change means the change of capacitance under				
		room temp.	specified flexure of substrate from the capacitance measured before				
		* Measurement to be made after keeping at room temp. for	the test.)				
44		24±2 hrs. * Solder temperature: 260±5°C	<u> </u>				
11.	Resistance to	* Solder temperature: 260±5℃ * Dipping time: 10±1 sec	* No remarkable damage.				
	Soldering Heat	* Preheating: 120 to 150°C for 1 minute before imme rse the	* Cap change:				
		capacitor in a eutectic solder.	X7R/X5R: within ±7.5%				
		*Before initial measurement (Class II only): To apply de-aging	Y5V: within ±20%				
		at 150°C for 1hr then set for 24±2 hrs at room temp.	* Q/D.F., I.R. and dielectric strength: To meet initial requirements.				
		*Cap. / DF(Q) / I.R. Measurement to be made after de-aging a 150℃ for 1hr then set for 24±2 hrs at room temp.	* 25% max. leaching on each edge.				
	1	:					

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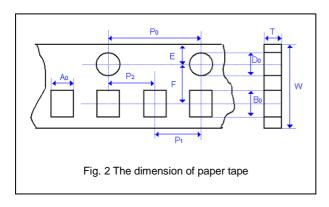
No.	Item		Test Condition	1	Requirements	
12.	Temperature	* Conduc	t the five cycles according to th	e temperatures and	* No remarkable damage.	
	Cycle	time.			* Cap change :	
		Step	Temp. (℃)	Time (min.)	X7R/X5R: within ±7.5%	
		1	Min. operating temp. +0/-3	30±3	Y5V: within ±20%	
		2	Room temp.	2~3	* Q/D.F., I.R. and dielectric strength: To meet initial requirement	S.
		3	Max. operating temp. +3/-0	30±3		
		4	Room temp.	2~3		
		- 8	nitial measurement (Class II on for 1hr then set for 24±2 hrs at I	,, ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	3	
		* Cap. / D	F(Q) / I.R. Measurement to be	made after de-aging		
		at 150℃ f	or 1hr then set for 24±2 hrs at	room temp.		
13.	Humidity	* Test ten	np.: 40±2℃		*No remarkable damage.	
	(Damp Heat)	* Humidit	y: 90~95% RH		*Cap change: X7R/X5R: within ±25% Y5V: within ±30%; 6.3V, within +30/-40%	
	Steady State	* Test tim	e: 500+24/-0hrs.		*Q/D.F. value:	
		* Before i	nitial measurement (Class II on	lly): To apply de-aging	g X7R/X5R:	
		at 150℃ 1	or 1hr then set for 24±2 hrs at	room temp.	Rated vol. D.F.	
		* Cap. / D	F(Q) / I.R. Measurement to be	made after de-aging	• I	
		at 150℃ f	or 1hr then set for 24±2 hrs at	room temp.	25V, 16V ≤15%	
					10V ≤20%	
					50V, 6.3V ≤30%	
				化有	Y5V: Rated vol. D.F.	
			过拉	PIT H	Rated vol. D.F. 50V ≤10%	
				上阳化	25V ≤15%	
			The second secon	17000000000000000000000000000000000000	16V, 10V ≤20%	
			Till on La	1	*I.R.: 1GΩ or RxC ≥ 10 Ω-F whichever is smaller.	
1.1		* T4 4			*No remarkable damage.	
14.	Humidity		np.: 40±2℃		*Cap change: X7R/X5R: within ±25%	
	(Damp Heat)	- E	y: 90~95%RH	254	Y5V: within ±30%; 6.3V, within +30/-40%	
	Load		e: 500+24/-0 hrs.	SSIVE SYSTEM AL	*Q/D.F. value:	
			/ voltage : Rated voltage.	hA. Ta analis da antan	X7R/X5R:	
		3	nitial measurement (Class II on for 1hr then set for 24±2 hrs at I	,, ,,,,	Rated vol. D.F.	
		1	PF(Q) / I.R. Measurement to be	·	100V ≤7.5%	
			for 1hr then set for 24±2 hrs at		250, 160 ≤15%	
		at 150 C			10V ≤20%	
			(3/1/7	CHNOLOGY CORPOR	[50V, 6.3V ≤30%	
				CHANDIACY CODDOR	Y5V:	
				TOTOUS CONTO	Rated vol. D.F.	
					25V ≤15%	
					16V, 10V ≤20%	
					*I.R.: 500MΩ or RxC≧5 Ω-F whichever is smaller.	
15	High	* Test tem	p. :			
13.			R/X7E: 125±3℃		*No remarkable damage. *Cap change: X7R/X5R: within ±25%	
	Temperature		V: 85±3℃		Y5V: within ±30%; 6.3V, within ±30/-40%	
	Load	:	e: 1000+24/-0 hrs. / voltage: 150% of rated voltage	2	*Q/D.F. value:	
	(Endurance)		f rated voltage for below range.		X7R/X5R:	
		Size	Dielectric Rated	Capacitance	Rated vol. D.F.	
			voltage	range	100V ≤7.5%	
		TT15 TT18	X5R 6.3V Y5V 6.3V,10V	<u>C≧1.0µF</u> C≧2.2µF	25V, 16V ≤15%	
		TT21	Y5V 6.3V	C≧2.2μ1 C≧10μF	10V ≤20%	
			X5R/X7R/X6S ≤10V	C≧10µF	50V, 6.3V ≤30%	
		TT31	Y5V 6.3V	C≧22µF	Y5V:	
		*Before ir	nitial measurement (Class II onl	y): To apply de-aging	Rated vol. D.F.	
			or 1hr then set for 24±2 hrs at	•	50V ≤10%	
			F(Q) / I.R. Measurement to ©r	de-aging at 150℃ for		
		inr then	set for 24±2 hrs at room temp.		[16V, 10V ≤20%	
					*I.R.: $1G\Omega$ or $RxC \ge 10$ Ω -F whichever is smaller.	

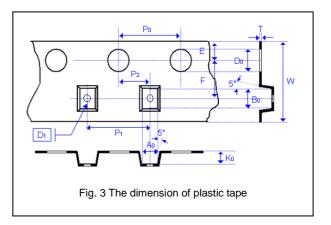
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APPENDIXES

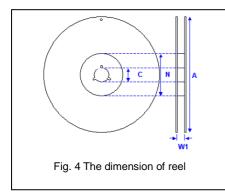
■ Tape & reel dimensions

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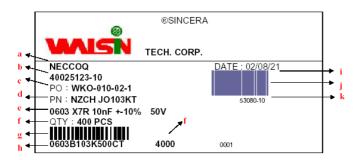
Size	0402	0603	0805	12	06	12	10
Thickness	L	Н	T ,	T	J	Т	K
A ₀	0.70 +/-0.2	1.05 +/-0.30	1.50 +/-0.20	1,90 +/-0.50	< 2.00	< 3.05	1.05 +/-0.30
B ₀	1.20 +/-0.2	1.80 +/-0.30	2.30 +/-0.20	3.50 +/-0.50	< 3.70	< 3.80	1.80 +/-0.30
Т	≦0.80	≦1.20	≦1.20	≦1.20	0.23 +/-0.1	0.23 +/-0.1	≦1.20
K ₀	-	/- <i>'</i>	4 -	- Y	< 2.50	< 1.50	-
w	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30
P ₀	4.00 +/-0.10	4.00 +/-0.10	+/-0.10	4.00 [€] +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
10xP ₀	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20
P ₁	2.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
P ₂	2.00 +/-0.05	2.00 +/-0.05	2.00	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05
D ₀	1.50 +0.1/-0	1.50 +0.1/-0	+0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0
D ₁	-	-	-	•	1.00 +/-0.10	1.00 +/-0.10	-
E	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10
F	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05



Size	040	0402, 0603, 0805, 1206, 1210						
Reel size	7"	10"	13"					
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2					
\mathbf{W}_1	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0					
Α	178.0±1.0	250.0±1.0	330.0±1.0					
N	60.0+1.0/-0	100.0±1.0	100±1.0					



Example of customer label

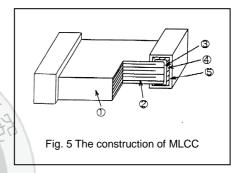


^{*}Customized label is available upon request

- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

Constructions

No.	Nam	ne	X7R, X5R, Y5V
①	Ceramic r	naterial	BaTiO₃ based
2	Inner ele	ctrode	斯阿恩
3		Inner layer	传吸份会
4	Termination	Middle layer	Ni Ni
(5)		Outer layer	Sn (Matt)



Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%, related humidity conditions.
- The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

served.

Multilayer Ceramic Capacitors

■ Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.

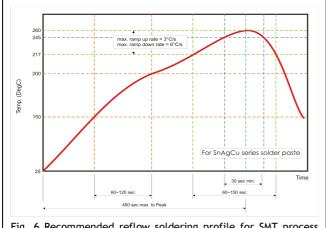


Fig. 6 Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.

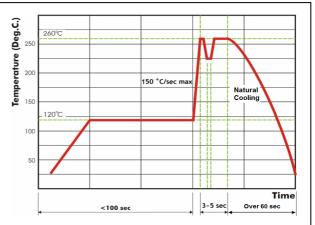


Fig. 7 Recommended wave soldering profile for SMT process with SnAgCu series solder.



served.

单击下面可查看定价,库存,交付和生命周期等信息

>>Walsin Technology(华新科技(华科))

>>点击查看相关商品